

## Preface

ICIAR 2004, the International Conference on Image Analysis and Recognition, was the first ICIAR conference, and was held in Porto, Portugal. ICIAR will be organized annually, and will alternate between Europe and North America. ICIAR 2005 will take place in Toronto, Ontario, Canada. The idea of offering these conferences came as a result of discussion between researchers in Portugal and Canada to encourage collaboration and exchange, mainly between these two countries, but also with the open participation of other countries, addressing recent advances in theory, methodology and applications.

The response to the call for papers for ICIAR 2004 was very positive. From 316 full papers submitted, 210 were accepted (97 oral presentations, and 113 posters). The review process was carried out by the Program Committee members and other reviewers; all are experts in various image analysis and recognition areas. Each paper was reviewed by at least two reviewing parties. The high quality of the papers in these proceedings is attributed first to the authors, and second to the quality of the reviews provided by the experts. We would like to thank the authors for responding to our call, and we wholeheartedly thank the reviewers for their excellent work in such a short amount of time. We are especially indebted to the Program Committee for their efforts that allowed us to set up this publication.

We were very pleased to be able to include in the conference, Prof. Murat Kunt from the Swiss Federal Institute of Technology, and Prof. Mário Figueiredo, of the Instituto Superior Técnico, in Portugal. These two world-renowned experts were a great addition to the conference and we would like to express our sincere gratitude to each of them for accepting our invitations.

We would also like to thank Prof. Ana Maria Mendonça and Prof. Luís Corte-Real for all their help in organizing this meeting; Khaled Hammouda, the webmaster of the conference, for maintaining the Web pages, interacting with authors and preparing the proceedings; and Gabriela Afonso, for her administrative assistance. We also appreciate the help of the editorial staff from Springer for supporting this publication in the LNCS series.

Finally, we were very pleased to welcome all the participants to this conference. For those who did not attend, we hope this publication provides a brief view into the research presented at the conference, and we look forward to meeting you at the next ICIAR conference, to be held in Toronto, 2005.

# ICIAR 2004 – International Conference on Image Analysis and Recognition

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